

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/597,288	CHIDAMBARRAO ET AL.	
Examiner		Art Unit		Page 1 of 1
KENNETH HAMLIN		2893		

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,414,289	05-1995	Fitch et al.	257/329
*	B	US-6,680,508	01-2004	Rudeck, Paul	257/316
*	C	US-6,238,976	05-2001	Noble et al.	438/259
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Sub-50 nm P-Channel FinFET" Huang et al. IEEE Transactions on Electron Devices. Vol. 48, No. 5, May 2001.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.